### DISCRETE SEMICONDUCTORS

## DATA SHEET

# BT131W series Triacs logic level

**Product specification** 

January 2004



### Triacs logic level

BT131W series

### **GENERAL DESCRIPTION**

Passivated, sensitive gate triacs in a plastic envelope suitable for surface mounting, intended for use in general purpose bidirectional switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

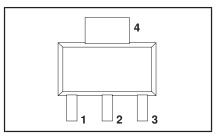
### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
V <sub>DRM</sub> I <sub>T(RMS)</sub> I <sub>TSM</sub>	BT131W- Repetitive peak off-state voltages RMS on-state current Non-repetitive peak on-state current	<b>500</b> 500 1 12.5	<b>600</b> 600 1 12.5	V A A

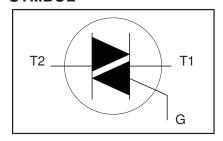
### **PINNING - SOT223**

PIN	DESCRIPTION
1	main terminal 1
2	main terminal 2
3	gate
tab	main terminal 2

### PIN CONFIGURATION



### **SYMBOL**



### LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT
$V_{DRM}$	Repetitive peak off-state voltages		-	<b>-500</b> 500 <sup>1</sup>	<b>-600</b> 600 <sup>1</sup>	\ \
I <sub>T(RMS)</sub>	RMS on-state current Non-repetitive peak on-state current	full sine wave; $T_{sp} \le 110 ^{\circ}\text{C}$ full sine wave; $T_{j} = 25 ^{\circ}\text{C}$ prior to surge	-	1		А
		t = 20 ms t = 16.7 ms	- -		2.5 3.8	A
l²t dl <sub>⊤</sub> /dt	I <sup>2</sup> t for fusing Repetitive rate of rise of on-state current after	t = 10  ms $I_{TM} = 1.5 \text{ A}; I_{G} = 0.2 \text{ A};$ $dI_{G}/dt = 0.2 \text{ A}/\mu\text{s}$	-	0.		A A <sup>2</sup> s
	triggering	T2+ G+ T2+ G- T2- G- T2- G+	- - -	5	0 0 0	Α/μs Α/μs Α/μs Α/μs
I <sub>GM</sub> V <sub>GM</sub> P <sub>GM</sub>	Peak gate current Peak gate voltage Peak gate power	12- 07	- - -	, , , , , , , , , , , , , , , , , , ,	5	V W
$ \begin{array}{c} P_{G(\text{AV})}^{\text{cm}} \\ T_{\text{stg}} \\ T_{j} \end{array} $	Average gate power Storage temperature Operating junction temperature	over any 20 ms period	- -40 -	15	.5 50 25	Ç W

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<sup>1</sup> Although not recommended, off-state voltages up to 800V may be applied without damage, but the triac may switch to the on-state. The rate of rise of current should not exceed 3  $A/\mu s$ .

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### THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
R <sub>th i-sp</sub>	Thermal resistance	full or half cycle	-	-	15	K/W
, ,	junction to solder point		-	-	-	K/W
R <sub>th j-a</sub>	Thermal resistance	pcb mounted; minimum footprint	-	156	-	K/W
,	junction to ambient	pcb mounted; pad area as in fig:14	-	70	-	K/W

### STATIC CHARACTERISTICS

 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I <sub>GT</sub>	Gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$				
		T2+ G	+	0.4	3	mA
		T2+ G		1.3	3	mA
		T2- G-		1.4	3	mA
		T2- G-	.   -	3.8	7	mA
I <sub>L</sub>	Latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$				
		T2+ G		1.2	5	mA
		T2+ G		4.0	8 5 8	mA
		<u>T</u> 2- G-		1.0	5	mĄ
		T2- G-	.   -	2.5		mA
l I <sub>H</sub>	Holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$	-	1.3	5_	mΑ
$\left  egin{array}{c} oldsymbol{I_{H}} \\ oldsymbol{V_{T}} \\ oldsymbol{V_{GT}} \end{array} \right $	On-state voltage	$I_{T} = 1.4 \text{ A}$	-	1.2	1.5	V
V <sub>GT</sub>	Gate trigger voltage	$\dot{V}_{D} = 12 \text{ V}; I_{T} = 0.1 \text{ A}$	-	0.7	1.5	V
1.		$V_D^{\rm D} = 400 \text{ V}; I_T = 0.1 \text{ A}; T_{\rm i} = 125 ^{\circ}\text{C}$	0.2	0.3		V <sub>_</sub>
$I_{D}$	Off-state leakage current	$V_D = V_{DRM(max)}$ ; $T_j = 125$ °C	-	0.1	0.5	mA

### **DYNAMIC CHARACTERISTICS**

 $T_i = 25$  °C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
dV <sub>D</sub> /dt	Critical rate of rise of off-state voltage	$V_{DM} = 67\% V_{DRM(max)}; T_j = 125 °C;$ exponential waveform; $R_{GK} = 1 k\Omega$	10	20	-	V/μs
dV <sub>com</sub> /dt	Critical rate of change of commutating voltage	$V_{DM} = 400 \text{ V}; T_j = 125 \text{ °C};$ $dI_{com}/dt = 0.5 \text{ A/ms}$	2	-	-	V/μs
t <sub>gt</sub>	Gate controlled turn-on time	$I_{TM} = 1.5 \text{ A}; V_D = V_{DRM(max)}; I_G = 0.1 \text{ A}; dI_G/dt = 5 \text{ A}/\mu s$	-	2	-	μs

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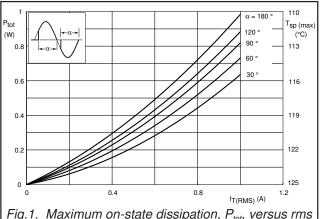


Fig.1. Maximum on-state dissipation,  $P_{tot}$ , versus rms on-state current,  $I_{T(RMS)}$ , where  $\alpha$  = conduction angle.

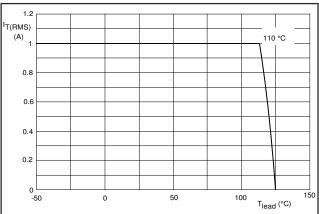


Fig.4. Maximum permissible rms current  $I_{\text{T(RMS)}}$ , versus solder point temperature  $T_{\text{sp}}$ .

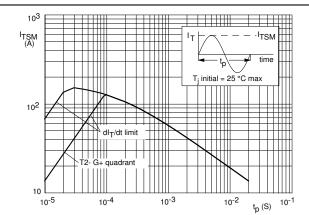


Fig.2. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus pulse width  $t_p$ , for sinusoidal currents,  $t_p \le 20$ ms.

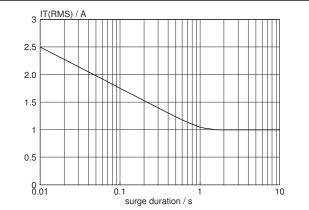


Fig.5. Maximum permissible repetitive rms on-state current  $I_{T(RMS)}$ , versus surge duration, for sinusoidal currents, f = 50 Hz;  $T_{lead} \le 110^{\circ}C$ .

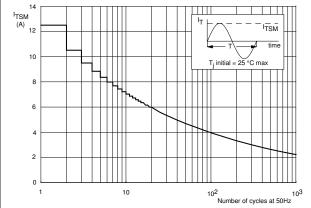


Fig.3. Maximum permissible non-repetitive peak on-state current  $I_{TSM}$ , versus number of cycles, for sinusoidal currents, f = 50 Hz.

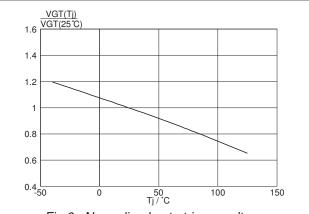
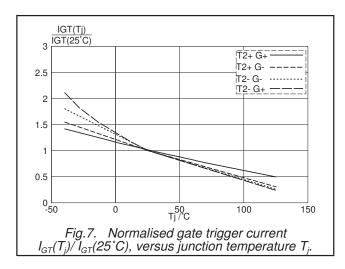


Fig.6. Normalised gate trigger voltage  $V_{GT}(T_j)/V_{GT}(25^{\circ}C)$ , versus junction temperature  $T_j$ .

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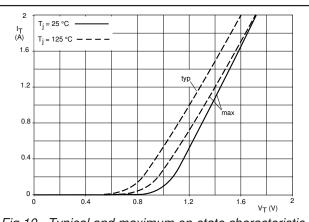
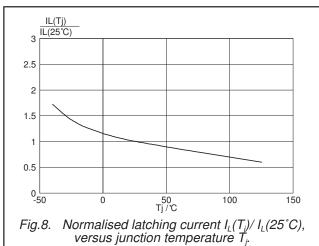


Fig.10. Typical and maximum on-state characteristic.



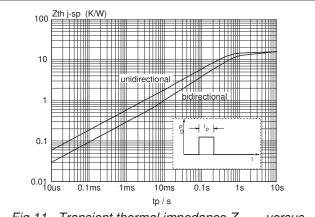
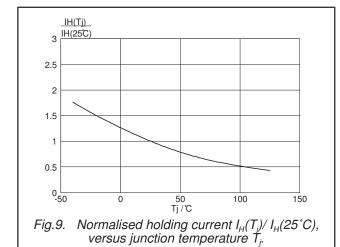


Fig.11. Transient thermal impedance  $Z_{th j-sp}$ , versus pulse width  $t_p$ .



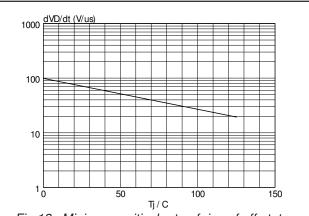
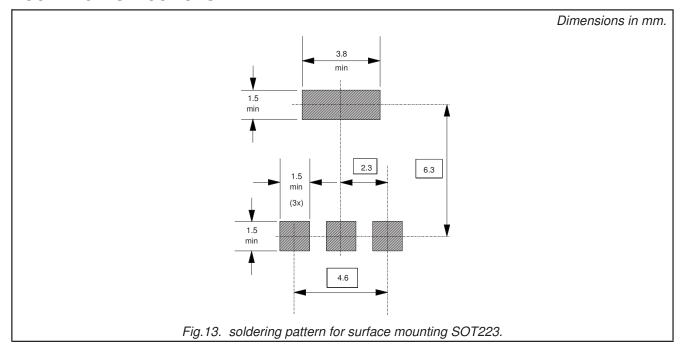


Fig.12. Minimum, critical rate of rise of off-state voltage,  $dV_D/dt$  versus junction temperature  $T_i$ .

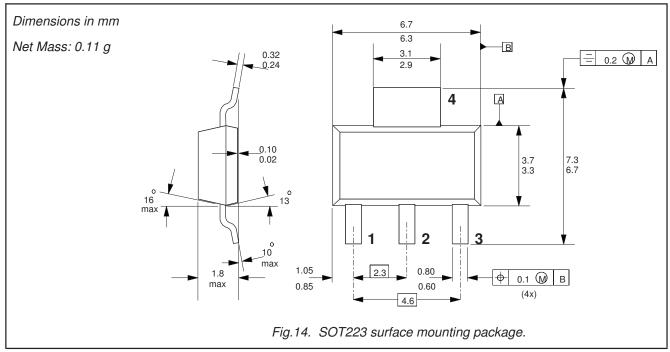
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### **MOUNTING INSTRUCTIONS**



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### **MECHANICAL DATA**



### **Notes**

- For further information, refer to Philips publication SC18 " SMD Footprint Design and Soldering Guidelines".
   Order code: 9397 750 00505.
   Epoxy meets UL94 V0 at 1/8".

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DOCUMENT STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)</sup>	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
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